May 2002

FAIRCHILD SEMICONDUCTOR

NDC7003P Dual P-Channel PowerTrench[®] MOSFET

General Description

These dual P-Channel Enhancement Mode Power Field Effect Transistors are produced using Fairchild's proprietary Trench Technology. This very high density process has been designed to minimize on-state resistance, provide rugged and reliable performance and fast switching. This product is particularly suited to low voltage applications requiring a low current high side switch.

Features

- -0.34A, -60 V. $R_{DS(ON)} = 5 \ \Omega \ @ V_{GS} = -10 \ V$ $R_{DS(ON)} = 7 \ \Omega \ @ V_{GS} = -4.5 \ V$
- Low gate charge
- Fast switching speed
- High performance trench technology for low RDS(ON)
- SuperSOT[™] -6 package: small footprint (72% smaller than standard SO-8); low profile (1mm thick)





Absolute Maximum Ratings T_A=25°C unless otherwise noted

ource Voltage ource Voltage urrent – Continuous – Pulsed Dissipation for Single Operation	(Note 1a) (Note 1a) (Note 1b)	-60 ±20 -0.34 -1 0.96 0.9	V V A W
urrent – Continuous – Pulsed	(Note 1a) (Note 1b)	-0.34 -1 0.96	A
– Pulsed	(Note 1a) (Note 1b)	-1 0.96	
	(Note 1b)	0.96	W
Dissipation for Single Operation	(Note 1b)		W
	` '	0.9	
	(Note 1c)	0.7	
ng and Storage Junction Tempera	ture Range	-55 to +150	°C
acteristics			
Thermal Resistance, Junction-to-Ambient (Note 1a)		130	°C/W
Thermal Resistance, Junction-to-Case (Note 1)		60	
	al Resistance, Junction-to-Ambient	al Resistance, Junction-to-Ambient (Note 1a)	al Resistance, Junction-to-Ambient (Note 1a) 130 al Resistance, Junction-to-Case (Note 1) 60

Device Marking	Device	Reel Size	Tape width	Quantity
.03P	NDC7003P	7"	8mm	3000 units

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	racteristics					
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{GS} = 0 V$, $I_D = -250 \mu A$	-60			V
<u>ΔBVdss</u> ΔTj	Breakdown Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}$, Referenced to 25°C		-57		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}} = -48 \text{ V}, V_{\text{GS}} = 0 \text{ V}$			-1	μA
I _{GSS}	Gate-Body Leakage,	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
On Cha	racteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250 \ \mu A$	-1	-1.9	-3.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}$, Referenced to 25°C		3.2		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$ \begin{array}{ll} V_{GS} = -10 \ V, & I_D = -0.34 \ A \\ V_{GS} = -4.5 \ V, & I_D = -0.25 \ A \\ V_{GS} = -10 \ V, I_D = -0.34 \ A, \ T_J = 125^\circ C \end{array} $		1.2 1.5 1.9	5 7.5 10	Ω
I _{D(on)}	On-State Drain Current	$V_{GS} = -10 \text{ V} \qquad V_{DS} = -10 \text{ V}$	-1			А
g fs	Forward Transconductance	$V_{DS} = -10 \text{ V}, \qquad I_D = -0.34 \text{ A}$		700		mS
Dynami	c Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = -25 V$, $V_{GS} = 0 V$,		66		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		13		pF
C _{rss}	Reverse Transfer Capacitance			6		pF
R _G	Gate Resistance	$V_{GS} = 15 \text{mV}, f = 1.0 \text{ MHz}$		11.2		Ω
Switchi	ng Characteristics (Note 2)					
t _{d(on)}	Turn–On Delay Time	$V_{DD} = -25 V$, $I_D = -1 A$,		3.2	6.4	ns
t _r	Turn–On Rise Time	$V_{GS} = -10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		10	20	ns
t _{d(off)}	Turn–Off Delay Time			8	16	ns
t _f	Turn–Off Fall Time			1	2	ns
Qg	Total Gate Charge	$V_{DS} = -25 \text{ V}, \qquad I_D = -0.34 \text{ A},$		1.6	2.2	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = -10 V$		0.3		nC
Q _{gd}	Gate-Drain Charge			0.3		nC
Drain-S	Source Diode Characteristics	and Maximum Ratings				
ls	Maximum Continuous Drain–Sourc	e Diode Forward Current			-0.34	А
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 V$, $I_{S} = -0.34 A$ (Note 2)		-0.8	-1.4	V

Notes:

1. R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $\rm R_{\theta JC}$ is guaranteed by design while $\rm R_{\theta CA}$ is determined by the user's board design.



2. Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%

Scale 1 : 1 on letter size paper

a) 130 °C/W when mounted on a 0.125 in² pad of 2 oz. copper.

b) 140°C/W when mounted on a .005 in² pad of 2 oz copper

c) 180°C/W when mounted on a minimum pad.

NDC7003P Rev B(W)

NDC7003P



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